

Thick800A

X-Ray Fluorescence Spectrometer



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Product Introduction

The instrument is specially designed for plating thickness measurement, rapid and non-destructive analysis for elements and contents of plating. The characteristics are as the following:

- Top lightening
- Up& down sample platform
- Movable platform with high accuracy
- Micro collimator
- Detector with high resolution
- Visual operation
- Auto height positioning
- Auto spot search
- Mouse positions the test point
- Excellent ray shielding
- Super large chamber design
- Safe protection of test interface



Technical Specifications

Detection range for plating: 25 elements such as

Cr \ Fe \ Ni \ Cu \ Zn \ Au \ Ag \ Pt \ Pd

Plating layers: 3 layers

Stability: 0.005~0.01 μ m; RSD: 0.1%

Arbitrary optional analysis and identification models

Independent matrix effect correction models

Multi-variable non-linear regression procedure

Excellent repeatability:0.1%

Long-time working stability:0.1%

Ambient temperature:15°C-15°C

Power supply:AC 220V \pm 5V.

purified stabilized voltage power supply

Application Fields

- Detection for plating thickness of metals, content of plating solution and plating.
- Detection for golden, platinum, silver, other precious metals and various jewelries content.
- Mainly applied in precious metal and jewelry processing industries; bank, jewelry selling and detection institution, electroplating industries.



Main performances

- Top-lightening: Meet the requirement for testing samples of different thicknesses and irregular shapes.
- Micro collimator: 0.1X1.0; can be used in testing micro point so as to improve testing accuracy.
- Movable platform with high accuracy: Repeated location accuracy is less than 0.005mm and the test point can be precisely located.
- Height laser: Auto height positioning ensures the testing for irregular samples, meanwhile protects the up & down platform.
- Auto spot search: Precisely locates spot to make sure the test point is aligned to the spot.
- Arbitrary measurement with mouse: Mouse can control the movable platform; it is able to click the test point by mouse.
- Detector with high resolution: Improve analysis accuracy.
- Safety: Excellent ray shielding; the test interface is protected by high sensitivity sensor.

Configuration

- Open sample chamber
- Double-laser locating device
- Lead glass shield cover.
- Si-Pin detector
- Detect electronic circuit by signal.
- Precise 2-D movable sample platform. The detection system can lift up and down to realize 3-D movement.
- High and low voltage power supply
- X-ray tube
- Altitude transducer
- Protection transducer
- Computer and ink jet printer

